The 10th Workshop on
Advances in Model Based Testing (A-MOST'14)

Co-located with IEEE International Conference on Software Testing, Verification and Validation (ICST'14)

April 4, 2014 in Cleveland, USA

Workshop Website: http://sites.google.com/site/amost2014

Important Dates:

Paper submission: January 20, 2014
Author notification: February 10, 2014
Camera-ready version due: February 16, 2014
Conference date: April 4, 2014

Theme and Goals: The increasing complexity of software results in new challenges for testing. Model Based Testing (MBT) continues to be an important research area, where new approaches, methods and tools make MBT techniques more deployable and useful for industry than ever. Models and different abstractions can ease comprehension of a complex system and ease test generation and automation. A-MOST has proven to be a successful workshop that brings researchers and practitioners together discussing formal and semi-formal approaches, specification formats and notations that contribute to simplifying complex aspects of a system. The goal is to bring researchers and practitioners together to discuss state of the art, practice and future prospects in MBT.

Topics of Interest: This workshop would like to encourage the submission of original papers that deal with any of the following topics, but not limited to:

- The models used in MBT
- The processes, techniques, and tools that support MBT
- Evaluation (i.e., the evaluation of software using MBT and the evaluation of MBT) Models
- Models for component, integration and system testing
- Product-line models & (Hybrid) embedded system models
- Systems-of-systems models & Architectural models
- Models for orchestration and choreography of services
- Executable models and simulation
- Environment and use models
- Non-functional models and quantitative MBT
- Model-based test generation algorithms
- Application of model checking techniques in model-based testing
- Tracing from requirements model to test models
- Performance and predictability of model-driven development
- Test model evolution during the software lifecycle
- Generation of testing-infrastructures from models
- Combinatorial approaches for MBT Statistical testing
- Estimating dependability (e.g., security, safety, reliability) using MBT
- Coverage metrics and measurements for structural and (non-)functional models
- Cost of testing, economic impact of MBT
- Empirical validation, experiences, case studies using MBT

Paper Formatting:

The submission format should not exceed 10 pages (including all text, figures, references and appendices) for research paper or 4 pages for experience reports and position papers. There are three types of papers: research papers, experience reports, and position papers. Each submitted paper must conform to the IEEE two-column publication format.

Submission and Proceedings:

Full papers should be submitted before January the 25th in PDF through easy-chair submission website at http://www.easychair.org/conferences/?conf=amost2014
Papers will be reviewed by at least three members from the program committee and notice of accepted papers will be sent before February the 10th.
Accepted papers must be orally presented during the workshop to be published within ICST proceedings. Accepted papers will be published in the IEEE Digital Library.

Program Chairs:

Levi Lúcio, McGill University, Canada
Tejeddine Mouelhi, University of Luxembourg, Luxembourg

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